

Notice of References Cited		Application/Control No. 10/589,324	Applicant(s)/Patent Under Reexamination FINLAY, ALAN	
		Examiner MICHAEL J. LOGIE	Art Unit 2881	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,458,699 A	07-1969	PADRTA FRANK G	250/288
*	B	US-3,992,626 A	11-1976	Bursack, William W.	250/288
*	C	US-4,023,398 A	05-1977	French et al.	73/23.2
*	D	US-4,201,913 A	05-1980	Bursack et al.	250/288
*	E	US-5,313,061 A	05-1994	Drew et al.	250/281
*	F	US-5,703,359 A	12-1997	Wampler, III, Francis M.	250/288
*	G	US-2005/0279932 A1	12-2005	Wang, Yang	250/290
*	H	US-7,367,216 B2	05-2008	Bonne, Ulrich	73/25.01
*	I	US-7,427,750 B2	09-2008	Grossenbacher et al.	250/288
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 01077855 A	03-1989	Japan	KOBAYASHI, TATSUJI	H01J 49/14
	O	JP 2001155677 A	06-2001	Japan	ARITA, YOSHIHIKO	H01J 49/04
	P	JP 2002357593 A	12-2002	Japan	ARITA, YOSHIHIKO	G01N 27/62
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.